
Crystallite size broadening

Structure Analysis
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Degree of being "out-of-phase" that can be tolerated vs.
crystallite size

Cullity Chapter 5, 14-3, 14-4 & 14-6

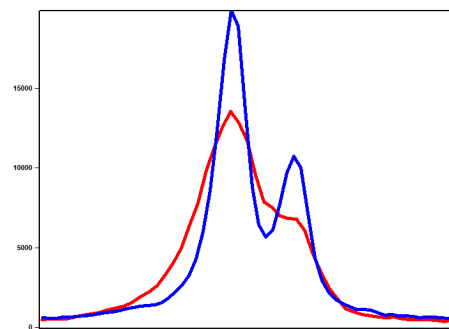
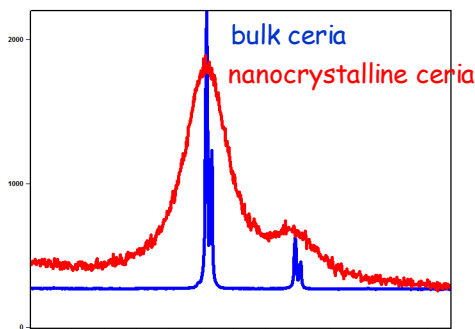
Hammond p180

Krawitz p343

Jenkins & Snyder p89

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Peak broadening



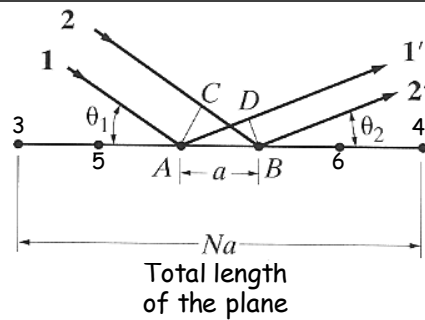
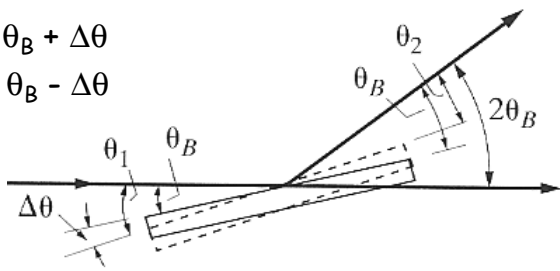
same sample run on two
different instruments

- Peak broadening may indicate:
 - ✓ Smaller crystallite size
 - ✓ More stacking faults, microstrain, and other defects in the crystal structure
 - ✓ An inhomogeneous composition in a solid solution or alloy
- Different instrument configurations can change the peak width, too

Geometrical factor - 1 of Lorentz Factor

$$\theta_1 = \theta_B + \Delta\theta$$

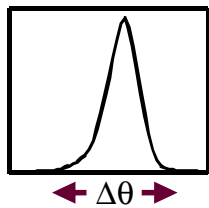
$$\theta_2 = \theta_B - \Delta\theta$$



$$\delta_{1'2'} = 2a\Delta\theta \sin \theta_B \rightarrow 2Na \Delta\theta \sin \theta_B$$

Path difference b/w rays scattered by atoms at either end of the plane (3 & 4)

Diffracted intensity = zero when $2Na \Delta\theta \sin \theta_B = \lambda$



$$\Delta\theta = \frac{\lambda}{2Na \sin \theta_B}$$

$$I_{\max} \propto 1/\sin \theta_B$$

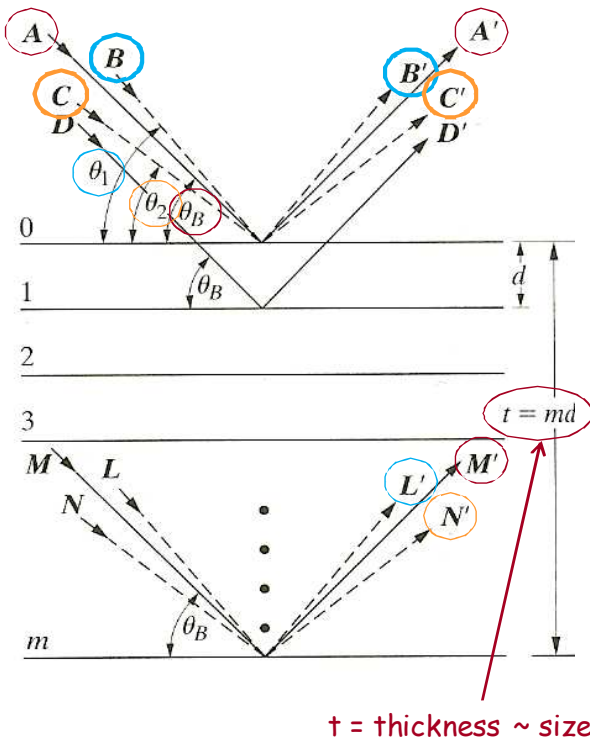
Size & strain broadening
 $B \propto 1/\cos \theta_B$

$$I_{\max} B \propto (1/\sin \theta_B) (1/\cos \theta_B) \propto \frac{1}{\sin 2\theta}$$

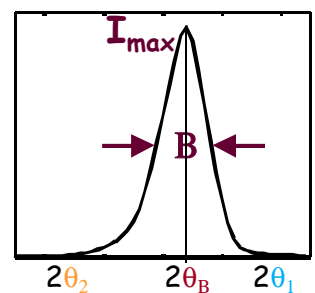
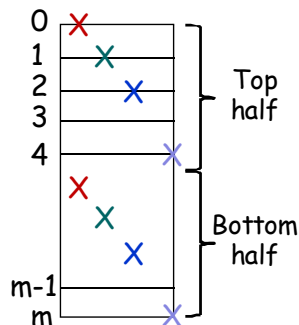
Max angular range of crystal rotation over which appreciable energy can be diffracted in the direction $2\theta_B$

Crystallite size broadening

$$\theta_1 = \theta_B + \Delta\theta (B, B') \quad \theta_2 = \theta_B - \Delta\theta (C, C')$$

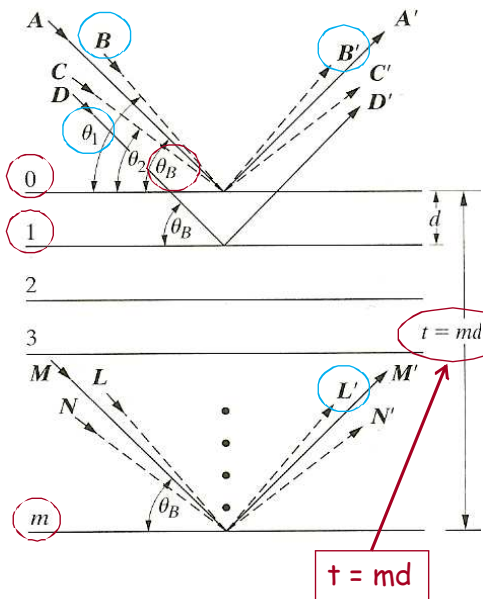


- $m + 1$ planes
- $\delta(A'D') = 1\lambda, \delta(A'M') = m\lambda$
- @ θ_1 or $\theta_2 \neq \theta_B$, incomplete destructive interference
- If $\delta(B'L') = (m+1)\lambda$, intensity zero
- If $\delta(C'N') = (m-1)\lambda$, intensity zero
- @ $2\theta_2 < 2\theta < 2\theta_1$, intensity is not zero



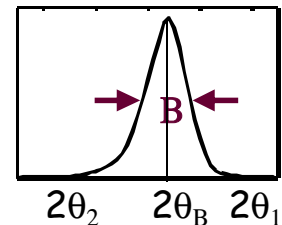
Crystallite size broadening

$\theta_1 = \theta_B + \Delta\theta$ (B, B') $\theta_2 = \theta_B - \Delta\theta$ (C, C') ➤ Ray B; $\theta_1 = \theta_B + \Delta\theta$, $\delta(B'L') = (m+1)\lambda$



- Compare when $m = 10$ and $m = 10,000$
- $m = 10 \rightarrow @ \theta_1, \delta(B'L') = \delta(0m) = 11\lambda, \delta(01) = 1.1\lambda$
- $m = 10,000 \rightarrow @ \theta_1, \delta(B'L') = \delta(0m) = 10,001\lambda, \delta(01) = 1.0001\lambda$
- $\theta_1(m = 10) \gg \theta_1(m = 10,000)$
- $\theta_1 \uparrow$ as $m \downarrow$ $\theta_2 \downarrow$ as $m \downarrow$
- $(2\theta_1 - 2\theta_2) \uparrow$ as $m \downarrow$
- $B \uparrow$ as thickness \downarrow
- Peak width \uparrow as size \downarrow

$$\begin{aligned} 2t \sin \theta_1 &= (m + 1)\lambda \\ 2t \sin \theta_2 &= (m - 1)\lambda \end{aligned} \quad \rightarrow \quad t(\sin \theta_1 - \sin \theta_2) = \lambda$$



Crystallite size broadening

Assume diffraction line is triangular in shape

$$B = \frac{1}{2}(2\theta_1 - 2\theta_2) = \theta_1 - \theta_2.$$

$$2t \sin \theta_1 = (m + 1)\lambda$$

$$2t \sin \theta_2 = (m - 1)\lambda$$

$$t(\sin \theta_1 - \sin \theta_2) = \lambda,$$

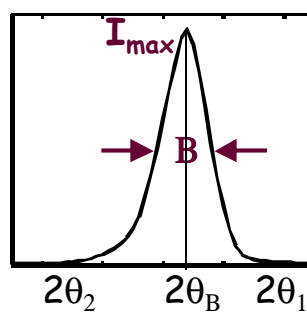
$$2t \cos\left(\frac{\theta_1 + \theta_2}{2}\right) \sin\left(\frac{\theta_1 - \theta_2}{2}\right) = \lambda$$

$$\theta_1 + \theta_2 = 2\theta_B \text{ (approx.)}$$

$$\sin\left(\frac{\theta_1 - \theta_2}{2}\right) = \left(\frac{\theta_1 - \theta_2}{2}\right) \text{ (approx.)}$$

$$2t \left(\frac{\theta_1 - \theta_2}{2}\right) \cos \theta_B = \lambda$$

$$t = \frac{\lambda}{B \cos \theta_B}$$



B; an angular width, in terms of 2θ (not a linear width)

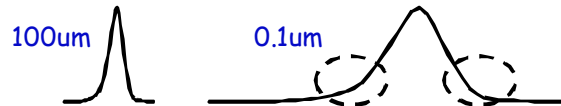
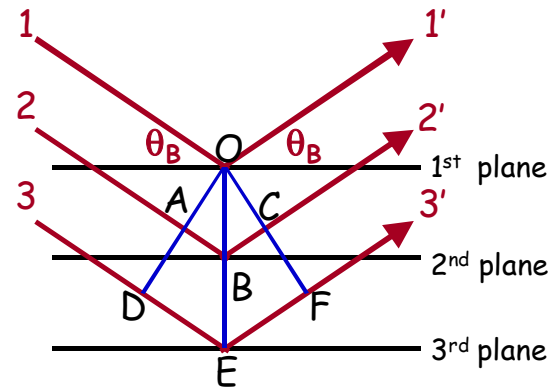
Shape factor; depends on the shape of the crystallites

$$t = \frac{0.9\lambda}{B \cos \theta_B}$$

Scherrer equation

Crystallite size broadening

- @ θ_B : $ABC = \lambda$, $DEF = 2\lambda \rightarrow$ diffraction peak
- $ABC = 0.5\lambda$, $DEF = 1\lambda \rightarrow$ no diffraction peak
- $ABC = 1.1\lambda$, $DEF = 2.2\lambda$
 - \rightarrow PD (path diff.) in 6th plane = 5.5λ
 - \rightarrow 1' & 6' out of phase \rightarrow no net diffraction
- $ABC = 1.001\lambda \rightarrow$ 1' & 501' out of phase; $ABC = 1.00001\lambda \rightarrow$ 1' & 50001' out of phase \rightarrow Sharp diffraction peak @ θ_B
- When crystal is only 100nm in size, 5000' or 50000' are not present
- Peak begins to show intensity at a lower θ and ends at a higher θ than $\theta_B \rightarrow$ particle size broadening
- Crystallites smaller than 1 μ m can cause broadening \rightarrow size can be determined using the peak width \leftarrow incomplete destructive interference

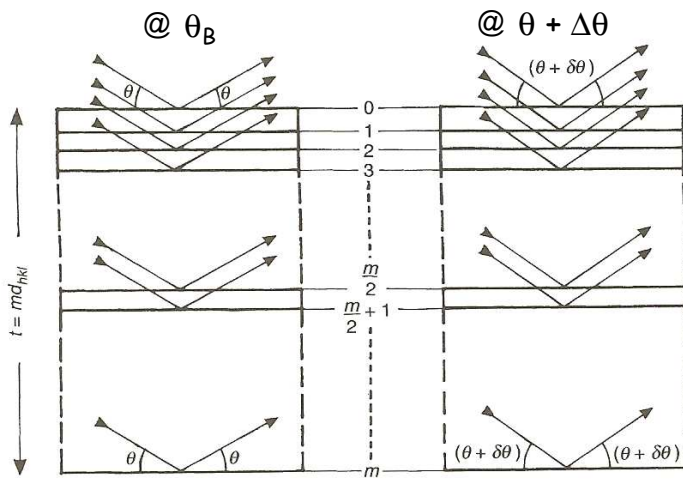


Crystallite size broadening

- In case $\lambda = 1.5 \text{ \AA}$, $d = 1.0 \text{ \AA}$, $\theta = 49^\circ$,
- $$t = \frac{0.9\lambda}{B \cos \theta_B}$$
- 1mm(millimeter) diameter crystal $\rightarrow 10^7$ parallel lattice planes, $\sim 10^{-7}$ radian*, $\sim 10^{-5}$ degree \rightarrow too small to observe
 - 500 \AA diameter crystal \rightarrow 500 parallel lattice planes, $\sim 10^{-3}$ radian, ~ 0.2 degree \rightarrow measurable
 - Non-parallel incident beam, non-monochromatic incident beam \rightarrow diffraction @ angles not exactly satisfying Bragg's law \rightarrow line broadening

* $B = (0.9 \times 1.5 \times 10^{-10}) / (10^{-3} \times \cos 49^\circ) \sim 2 \times 10^{-7} \text{ rad}$

Crystallite size broadening



between planes 0 & $(m/2)$

Constructive interference at angle θ

$$(m/2)\lambda = (m/2)2d_{hkl} \sin \theta.$$

Destructive interference at angle $\theta + \delta\theta$

$$(m/2)\lambda + \lambda/2 = (m/2)2d_{hkl} \sin(\theta + \delta\theta)$$

$$\delta(1, (m/2)+1) = 0.5\lambda$$

$$\cos \delta\theta = 1 \text{ and } \sin \delta\theta \approx \delta\theta$$

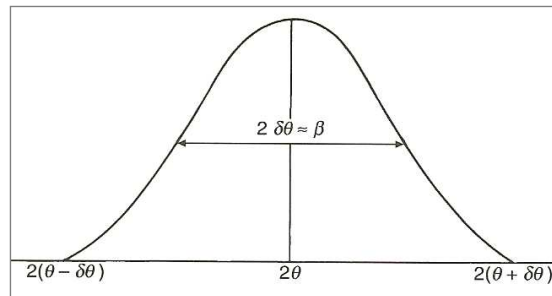
$$(m/2)\lambda + \lambda/2 = (m/2)2d_{hkl} \sin \theta + (m/2)2d_{hkl} \cos \theta \delta\theta$$

$$md_{hkl} = t$$

$$2\delta\theta = \frac{\lambda}{t \cos \theta}$$

$$B = \beta = \frac{\lambda}{t \cos \theta} = \frac{\lambda \sec \theta}{t}$$

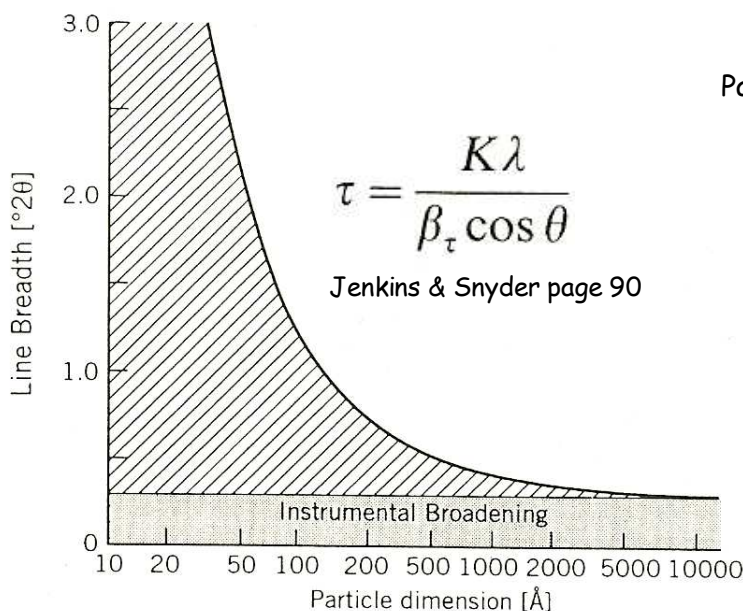
Scherrer equation



Crystallite size broadening

Scherrer equation

$$t = \frac{0.9\lambda}{B \cos \theta_B}$$



$$\tau = \frac{K\lambda}{\beta_{\tau} \cos \theta}$$

Jenkins & Snyder page 90

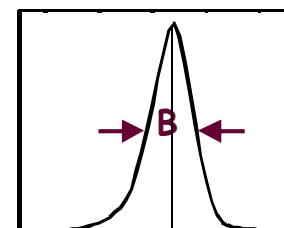
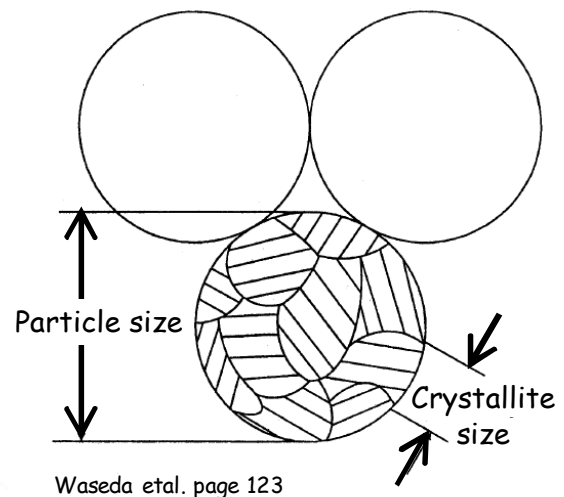
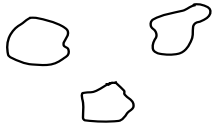


Figure 3.21. Line width as a function of particle dimension.

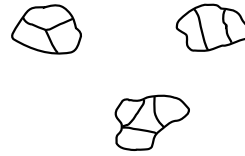
Particle size vs. Crystallite size

Particles can be individual crystallites



Particle size = crystallite size

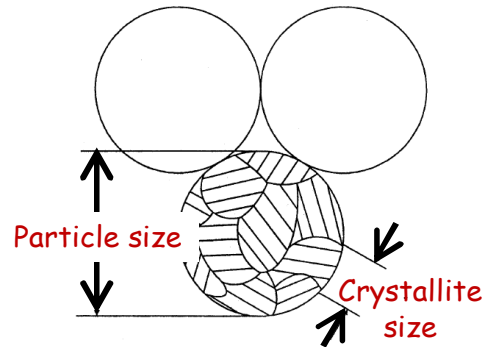
Particles may be imperfect single crystals



Particle size > crystallite size

- Individual crystallites are perfect
- Boundaries
 - Dislocations
 - Twin walls
 - Anti-phase walls
 - Stacking faults

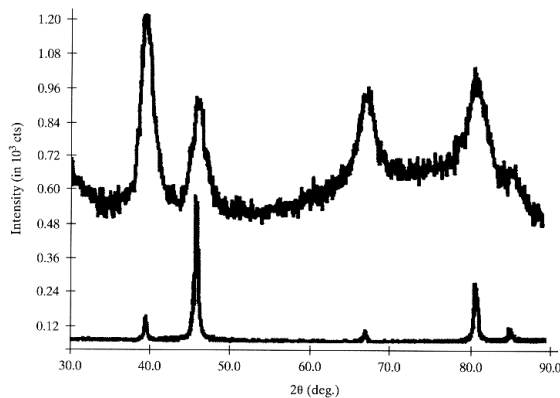
From presentation of Dr. Mark Rodriguez
@ DXC 2017 "What usually causes trouble?"



Waseda et al. page 123

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Crystallite size broadening



platinum nano-particle in a matrix of amorphous carbon

rolled platinum sheet

<i>hkl</i>	FWHM ($^{\circ}2\theta$)	<i>t</i> (Å)
111	1.9	50
200	1.7	55
220	2.1	50
311	2.5	45-50

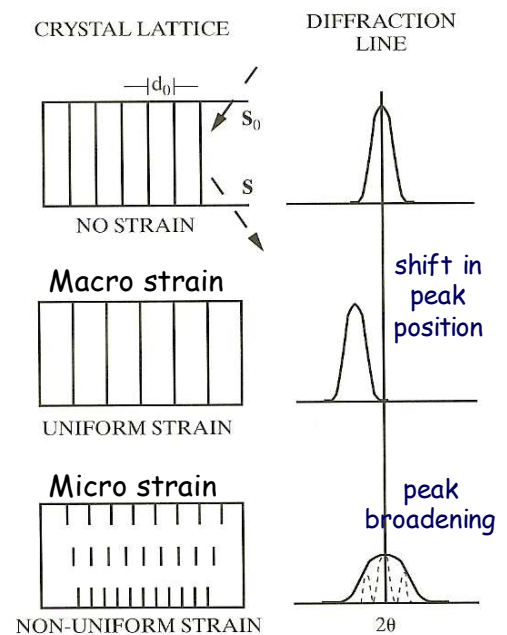
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Strain broadening

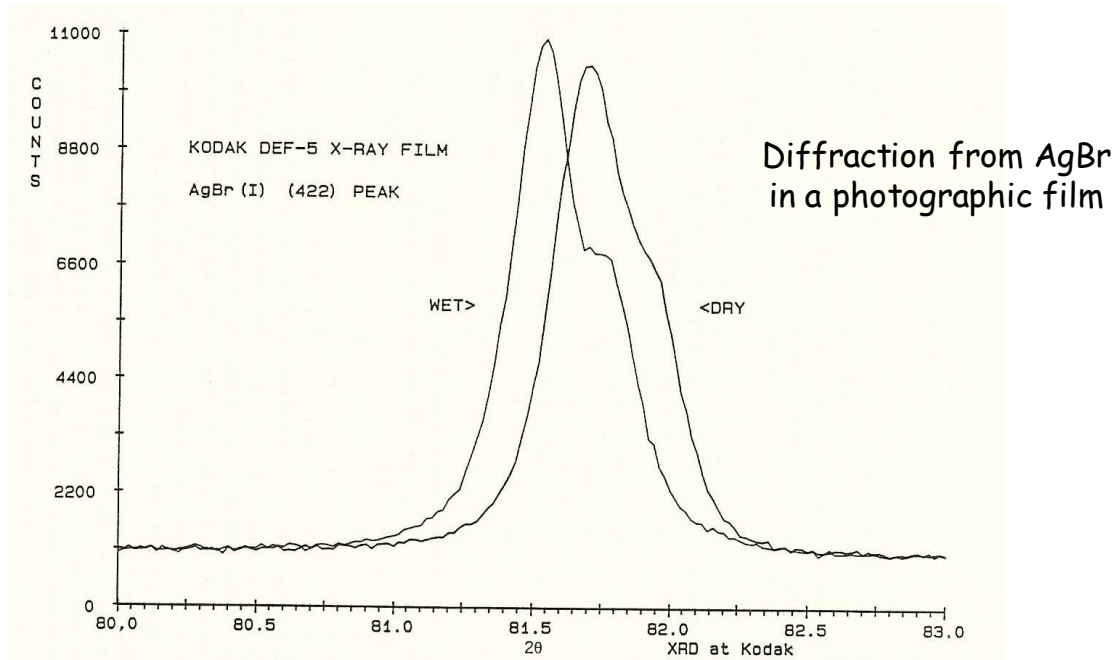
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Strain/Stress

- Macrostrain/Macrostress → shift in peak position
 - ✓ stress is uniformly compressive or tensile over large distances ← lattice parameter measurement
- Microstrain/Microstress → peak broadening
 - ✓ Distribution of both tensile & compressive stress → distribution of d-values
 - ✓ Can come from dislocations, vacancies, defects, shear planes, thermal expansion/contraction, etc. ← peak profile analysis



Peak shift ← macrostrain

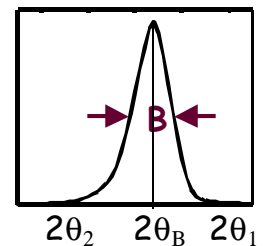


Differential expansion between the film substrate & AgBr causes macrostrain → changes lattice parameter → peak shift

Strain broadening, Size & Strain broadening

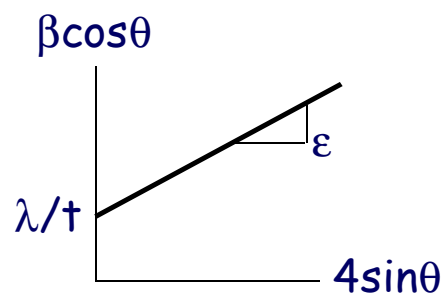
- $\lambda = 2d \sin\theta$
- $0 = 2d \cos\theta \delta\theta + 2 \sin\theta \delta d$
- $\Delta(2\theta) = -2(\delta d/d)\tan\theta = B$; extra broadening produced by microstrain
- $\beta_\epsilon = 4\epsilon \tan\theta$ (Jenkins & Snyder p93)
- $\beta = -2\epsilon \tan\theta$ (Hammond p214)

Strain broadening



Size & Strain broadening


- $\beta_{\text{size}} = \lambda/(t\cos\theta)$, $\beta_{\text{strain}} = 4\epsilon \tan\theta$, $\beta_{\text{instrument}}$
- $\beta(\text{total}) = \lambda/(t\cos\theta) + 4\epsilon \tan\theta + \beta_{\text{instrument}}$
- $\beta = \lambda/(t\cos\theta) + 4\epsilon (\sin\theta/\cos\theta)$
- $\beta \cos\theta = \lambda/t + 4\epsilon \sin\theta$
- $\beta \cos\theta/\lambda = 1/t + (4\epsilon \sin\theta)/\lambda$
- plot $\beta \cos\theta/\lambda$ vs $\sin\theta/\lambda$ (**Williamson-Hall plot**) → can separate size & strain contributions to line broadening --- semi-quantitative

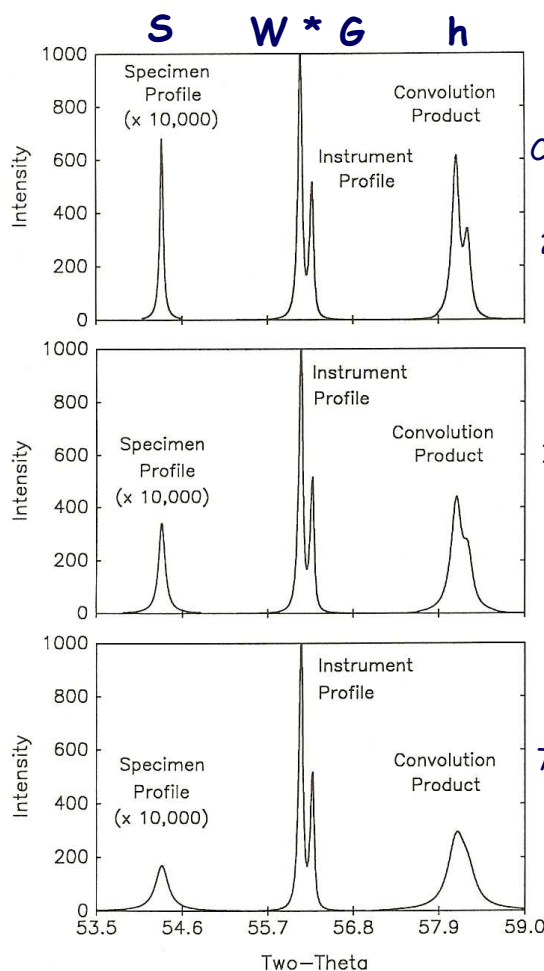


Broadening

- Darwin width
 - ✓ Incident photon is confined to certain volume
 - ✓ Result of uncertainty principle ($\Delta p \Delta x = h$) --- Location of the photon in a xtal is restricted to a certain volume
 - ✓ Δp must be finite $\rightarrow \Delta \lambda$ must be finite \rightarrow finite width of diffraction peak
- Specimen contribution (S)
- Spectral distribution (radiation source contribution) (W)
- Instrumental contribution (G)

- $(W * G) \leftarrow$ X-ray source image, flat specimen, axial divergence of incident beam, specimen transparency, receiving slit, etc.
- $(W * G)$; fixed for a particular instrument/target system \rightarrow instrumental profile $g(x)$
- Overall line profile $h(x) = (W * G) * S + \text{background} = g(x) * S + \text{BKG}$


LaB₆ SRM



$$h(x) = (W * G) * S$$

Line shape \leftarrow convolution of a profile representing instrument ($W*G$) and specimen (S) contributions

Integrated line intensity of the convolution product remains the same while the peak broadens and the peak intensity decreases

$$B_{obs} = B_{size / strain} + B_{inst} \quad \text{Lorentzian profile}$$

$$B_{obs}^2 = B_{size / strain}^2 + B_{inst}^2 \quad \text{Gaussian profile}$$

Standard Reference Materials (SRMs)

- Powder Line Position + Line Shape Std for Powder Dif
 - ✓ Silicon (SRM 640e); \$741/7.5g
- Line position - Fluorophlogopite mica (SRM 675); \$721/7.5g
- Line profile - LaB₆ (SRM 660c); \$1,002/6g
- Intensity
 - ✓ ZnO, TiO₂ (rutile), Cr₂O₃, CeO₂ (SRM 674b); \$916/10g
- Quantitative phase analysis
 - ✓ Al₂O₃ (SRM 676a); "notify me"/20g, Silicon Nitride (SRM 656); \$492/20g
- Instrument Response Std
 - ✓ Alumina plate (SRM 1976b); \$700/1 disc

Prices; 2017-12-28
www.nist.gov/srm/index.cfm

Gold
 \$41.46 / gram
 (2017-12-28)
goldprice.org

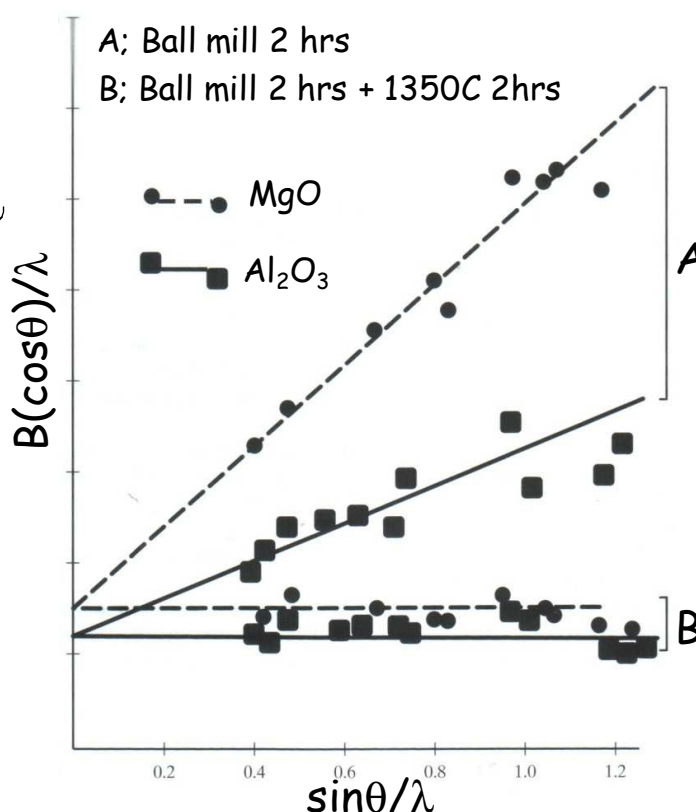
Conventional Williamson-Hall Plot

➤ Size + Strain

$$\underbrace{\frac{B \cos \theta}{\lambda}} = \underbrace{\frac{0.9}{d}} - 2 \underbrace{\frac{\Delta d}{d}} \underbrace{\frac{\sin \theta}{\lambda}}$$

$$y = a + bx$$

- Size ≫ strain
 - ✓ Horizontal line
- Size ≪ strain
 - ✓ Linear function



Modified Williamson-Hall Plot

The effect of dislocation contrast on x-ray line broadening: A new approach to line profile analysis

T. Ungár^{a)} and A. Borbély

Institute for General Physics, Eötvös University Budapest, H-1445 Múzeum krt. 6-8, Budapest VIII, P.O.B. 323, Hungary

(Received 29 May 1996; accepted for publication 6 September 1996)

- explained strain broadening by dislocations

$$\frac{B \cos \theta}{\lambda} = \frac{0.9}{d} + \Delta K^D \quad y = a + X$$

Classical $X = -2 \frac{\Delta d}{d} \frac{\sin \theta}{\lambda}$

Modified $X = A(\rho^*)^{1/2} + A'(Q^*)^{1/2}$

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Modified Williamson-Hall Plot

$$\frac{B \cos \theta}{\lambda} = \frac{0.9}{d} + A(\rho^*)^{1/2} + A'(Q^*)^{1/2}$$

- ρ^* : (formal) dislocation density
- Q^* : (formal) two-particle correlations in the dislocation ensemble
- A, A' : parameter determined by dislocations

- True values of dislocation density, correlation factor

$$\rho^* = \rho(\pi g^2 b^2 \bar{C})/2 \quad Q^* = Q(\pi g^2 b^2 \bar{C})^2/4$$

✓ \bar{C} : average contrast factor of dislocation

✓ b : Burgers vector of dislocation

✓ Particular reflection

$$g = \frac{2 \sin \theta}{\lambda}$$

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Appl. Phys. Lett. 69 (21), 3173 (1996)

Conventional vs. Modified W-H Plot

$$y = a + X$$

Conventional

$$X = -2 \underbrace{\frac{\Delta d}{d}}_b \underbrace{\frac{\sin \theta}{\lambda}}_x$$

$$= bx$$

Modified

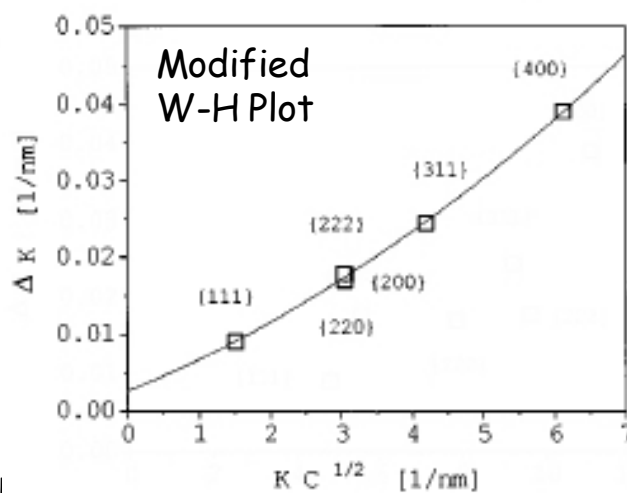
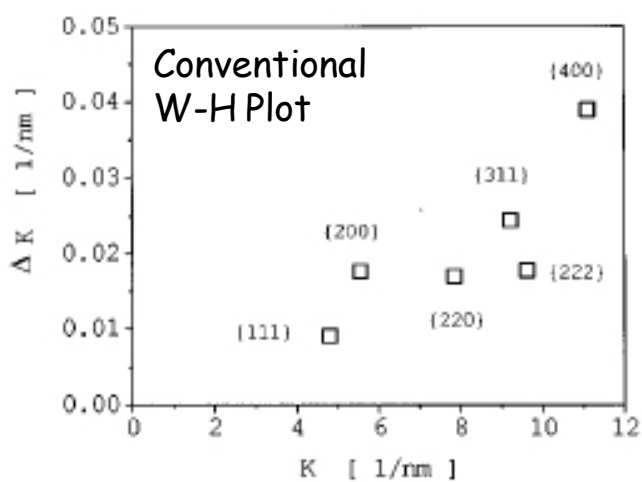
$$X = \underbrace{\left(\frac{\pi A b^2}{2}\right)^{1/2} \rho^{1/2}}_{b'} \underbrace{\frac{2 \sin \theta}{\lambda}}_{x'} C^{1/2}$$

$$+ \underbrace{\left(\frac{\pi A' b^2}{2}\right) Q^{1/2}}_{b''} \underbrace{\left(\frac{2 \sin \theta}{\lambda} C^{1/2}\right)^2}_{x'^2}$$

$$= b' x' + b'' x'^2$$

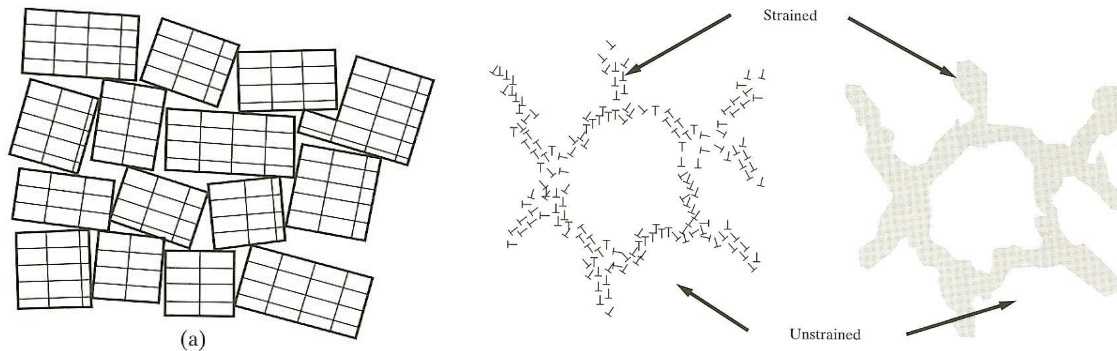
$$K = 2 \frac{\sin \theta}{\lambda}$$

Conventional vs. Modified W-H Plot



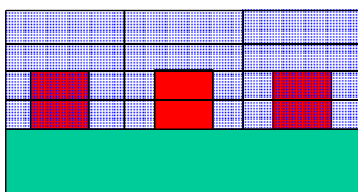
Mosaic structure

- Angle of disorientation between the tiny blocks is ϵ → **diffraction occur at all angles between θ_B and $\theta_B + \epsilon$**
- **Increases the integrated intensity** relative to that obtained (or calculated) for an ideally perfect crystal ← strains & strain gradients associated with the groups of dislocations



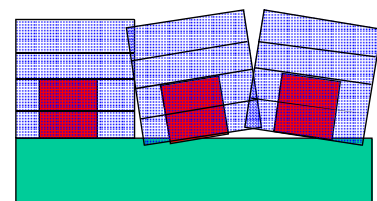
Mosaic Spread

- Mosaicity is created by slight misorientations of different crystals as they nucleate and grow on the substrate. When the crystals join, they form low energy grain boundaries.



In an ideal case, each nuclei (red) is perfectly oriented.

When the crystals grow and meet, there is perfect bounding between the crystallites → no grain boundary.



If the nuclei (red) are slightly misaligned, then low angle grain boundaries will be formed.

Mosaic Spread - reciprocal space

- Mosaic Spread can be quantified by measuring the broadening of the lattice point in reciprocal space
- The amount of broadening of the reciprocal lattice point that is perpendicular to the reflecting plane normal can be attributed to mosaic spread
- The peak broadening parallel to the interface can be attributed to lateral correlation length

